

Search Notes

Application/Control No.

10/657,100

Examiner

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Applicant(s)/Patent under
Reexamination

ARAKAWA, TAKEHARU

Art Unit

2617

SEARCHED

Class	Subclass	Date	Examiner
455	566 550.1 422.1 73 457 414.1 414.3	2/16/2007	

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
see	attached	2/16/2007	KN

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East (see attached)	2/16/2007	KN
Sony Trinh	2/14/2007	KN